

# Learning Temporal Properties from Event Logs via Sequential Analysis

Francesco Chiariello

IRIT, ANITI, University of Toulouse

Contact: [francesco.chiariello@irit.fr](mailto:francesco.chiariello@irit.fr)

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# Sequential Analysis

Statistical hypothesis testing approach with the following features:

- **Sequential Data Processing:** Data are examined in sequence, often as soon as they become available.
- **Step-by-Step Decision Making:** At each step, decide to accept, reject, or gather more data based on the evidence.
- **Data Efficiency:** More efficient than traditional approaches, which process data in large batches.
- **Robustness to Noise:** Based on statistical principles.

# Sequential Analysis in Quality Control



# Event Logs and Processes

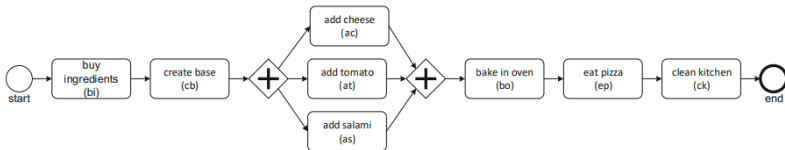


Figure: Pizza Process (from the Process Mining Handbook)

- A **process trace** is a sequence of activities from start to end.
- An **event log** is a sequence of traces.
- Traces may be affected by **noise**.

# Linear Temporal Logic on Process Traces ( $LTL_p$ )

- An  $LTL_p$  formula  $\varphi$  over a set of activities  $\Sigma$  is defined by the following grammar:

$$\varphi ::= a \mid \neg\varphi \mid \varphi \wedge \varphi \mid X(\varphi) \mid \varphi U \varphi$$

- Common abbreviations are used: *true*,  $\rightarrow$ ,  $\vee$ ,  $F$ ,  $G$ .

# LTL<sub>p</sub> semantics

- Given a formula  $\varphi$ , a trace  $\pi = \pi_1, \pi_2, \dots, \pi_{len(\pi)} \in \Sigma^+$ , and a time instant  $i$ , with  $1 \leq i \leq len(\pi)$ , the semantics is defined as follows:
  - $\pi, i \models a$  iff  $a = \pi_i$ ,
  - $\pi, i \models \neg\varphi$  iff  $\pi, i \not\models \varphi$ ,
  - $\pi, i \models \varphi_1 \wedge \varphi_2$  iff  $\pi, i \models \varphi_1$  and  $\pi, i \models \varphi_2$ ,
  - $\pi, i \models X\varphi$  iff  $i < len(\pi)$  and  $\pi, i + 1 \models \varphi$ ,
  - $\pi, i \models \varphi_1 U \varphi_2$  iff  $\pi, j \models \varphi_2$  for some  $j$ , with  $i \leq j \leq len(\pi)$ , and  $\pi, k \models \varphi_1$  for all  $k = i, \dots, j - 1$ .
- We write  $\pi \models \varphi$ , and we say that  $\pi$  satisfies  $\varphi$ , if  $\pi, 1 \models \varphi$ .

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  - Select a candidate formula.
  - Select the  $n$ -th trace.
  - Compute the number of defects of the trace w.r.t. the formula.
  - Add it to the cumulative error  $defects_n$
  - If:
    - $defects_n \leq A_n$  we accept the formula.
    - $defects_n \geq R_n$  (with  $R_n > A_n$ ) we reject the formula.
    - if  $A_n < defects_n < R_n$  we select the  $(n + 1)$ -th trace and repeat.

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- **Question 1:** How do we select the thresholds?
- **Question 2:** How do we count the number of defects?

# Sequential Probability Ratio Test (SPRT)

- Let  $p$  denote the probability of a defect,  $p_0$  a tolerable value, and  $p_1 > p_0$  an intolerable one.
- The null hypothesis is  $H_0 : p = p_0$ , while the alternative hypothesis is  $H_1 : p = p_1$ .
- SPRT defines  $A_n$  and  $R_n$  as:

$$A_n = \frac{\ln\left(\frac{\beta}{1-\alpha}\right)}{\ln\left(\frac{p_1}{p_0}\right) - \ln\left(\frac{1-p_1}{1-p_0}\right)} + n \frac{\ln\left(\frac{1-p_0}{1-p_1}\right)}{\ln\left(\frac{p_1}{p_0}\right) - \ln\left(\frac{1-p_1}{1-p_0}\right)},$$
$$R_n = \frac{\ln\left(\frac{1-\beta}{\alpha}\right)}{\ln\left(\frac{p_1}{p_0}\right) - \ln\left(\frac{1-p_1}{1-p_0}\right)} + n \frac{\ln\left(\frac{1-p_0}{1-p_1}\right)}{\ln\left(\frac{p_1}{p_0}\right) - \ln\left(\frac{1-p_1}{1-p_0}\right)}$$

where the parameters  $\alpha$  and  $\beta$  allows to control type I and type II errors, respectively.

## SPRT (cont'd)

- We can therefore rewrite  $A_n$  and  $R_n$  as:

$$A_n = mn + c_A,$$

$$R_n = mn + c_R,$$

with  $m > 0$ ,  $c_A < 0$ , and  $c_R > 0$ .

# Trace Alignment

- **Trace Alignment** is the problem of aligning a trace  $\pi$  with a formula  $\varphi$ , producing a new trace  $\pi'$  satisfying  $\varphi$ .
- Actions:
  - add(?activity), of cost 1,
  - del, of cost 1,
  - read, of cost 0.
- Repair a trace can be reduced to cost-optimal planning.

## Example

$$\varphi = G(a \rightarrow Fb)$$

$$\pi = aba$$

$$\pi' = ab\mathbf{a}$$

① read: a|ba

② read: ab|a

③ del: ab|

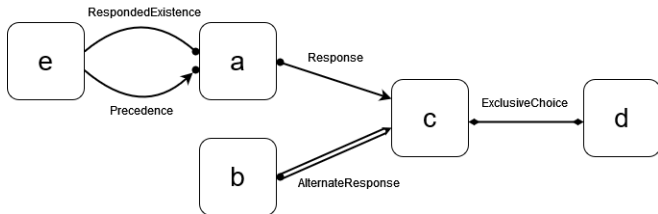
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# Declarative Model

We consider the declarative model over  $\Sigma = \{a, b, c, d, e\}$  specified by the following 5 constraints:

- (C1)  $ExclusiveChoice(c, d) \equiv F(c \vee d) \wedge \neg(Fc \wedge Fd)$   
 (C2)  $Response(a, b) \equiv G(a \rightarrow Fb)$   
 (C3)  $RespondedExistence(a, e) \equiv Fa \rightarrow Fe$   
 (C4)  $Precedence(e, a) \equiv (\neg a)We$   
 (C5)  $AlternateResponse(b, c) \equiv G(b \rightarrow X(\neg bUc))$





# Log Generation

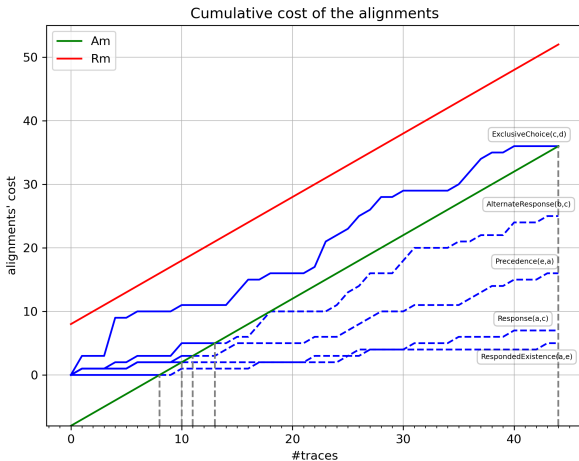
- We generate a log of 100 traces of length varying from 6 to 15. In particular, for each length, we generate 5 positive traces and 5 negative ones.

**Table:** Number of traces violating the constraints arranged according to the cost of repairs.

	1	2	3+	#traces	total cost
C1	19	13	6	38	68
C2	14	0	0	14	14
C3	9	0	0	9	9
C4	31	0	0	31	31
C5	16	15	2	33	52

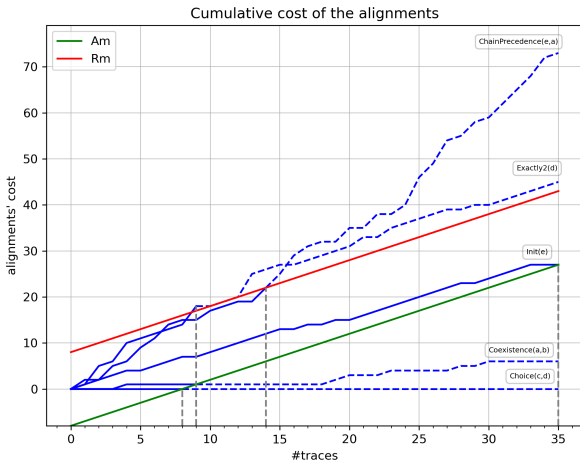
# Results

- We choose  $m = 1$ ,  $c_R = 8$ ,  $c_A = -8$ .



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# Conclusion and Future Work

## Contributions:

- Learn LTL formulae with sequential analysis.
- Quantify defects using trace alignment.
- Approach **robust** and **data-efficient**.

## Future Directions:

- Select candidate formulae.
- Learn full model.
- Quantitative semantics.

# Thank you for your attention!

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